- Members of the Texas Instruments Widebus ${ }^{\text {TM }}$ Family
- Inputs Are TTL-VoItage Compatible
- Provide Extra Data Width Necessary for Wider Address/Data Paths or Buses With Parity
- Flow-Through Architecture Optimizes PCB Layout
- Distributed $\mathrm{V}_{\mathrm{CC}}$ and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPICTM (Enhanced-Performance Implanted CMOS) $1-\mu \mathrm{m}$ Process
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings


## description

These 18 -bit flip-flops feature 3 -state outputs designed specifically for driving highly-capacitive or relatively low-impedance loads. They are particularly suitable for implementing wider buffer registers, I/O ports, parity bus interfacing, and working registers.

The 'ACT16823 can be used as two 9-bit flip-flops or one 18 -bit flip-flop. With the clock-enable (CLKEN) input low, the D-type flip-flops enter data on the low-to-high transitions of the clock. Taking CLKEN high disables the clock buffer, thus latching the outputs. Taking the clear ( $\overline{\mathrm{CLR} \text { ) input }}$ low causes the Q outputs to go low independently of the clock.

54ACT16823 . . . WD PACKAGE
74ACT16823 ... DL PACKAGE
(TOP VIEW)

| $1 \overline{\mathrm{CLR}}{ }^{1}$ | 56 | 1CLK |
| :---: | :---: | :---: |
| 10E ${ }^{\text {a }}$ | 55 | 1 1-LKEN |
| 1Q1 3 | 54 | 1 D 1 |
| GND 4 | 53 | $]$ GND |
| 1Q2 5 | 52 | 1 D 2 |
| 1Q3 6 | 51 | 1 1D3 |
| $\mathrm{v}_{\mathrm{CC}}{ }^{7}$ | 50 | $\mathrm{V}_{\mathrm{CC}}$ |
| 1Q4 8 | 49 | 1 154 |
| 1Q5 9 | 48 | 1 D 5 |
| 1Q6 10 | 47 | 1D6 |
| GND 11 | 46 | $]$ GND |
| 1Q7 12 | 24 | 1 D 7 |
| 1Q8 13 | 34 | 1D8 |
| 1Q9 14 | 43 | $1 \mathrm{D9}$ |
| 2Q1 15 | 42 | 2D1 |
| 2Q2 16 | 641 | 1 2D2 |
| 2Q3 17 | 78 | 2D3 |
| GND 18 | 39 | GND |
| 2Q4 19 | 38 | 2D4 |
| 2Q5 20 | - 37 | 2D5 |
| 2Q6[21 | 136 | 2D6 |
| $\mathrm{V}_{\mathrm{CC}}{ }^{22}$ | 25 | $\mathrm{V}_{\mathrm{CC}}$ |
| 2Q7 23 | 34 | 2D7 |
| 2Q8 24 | 33 | 2D8 |
| GND 25 | 32 | GND |
| 2Q9 26 | 31 | 2D9 |
| $2 \overline{\mathrm{OE}}{ }^{27}$ | 30 | $1 \mathrm{C} \overline{\text { LKEN }}$ |
| $2 \overline{\mathrm{CLR}} 28$ | $8 \quad 29$ | ] 2CLK |

A buffered output-enable ( $\overline{\mathrm{OE}})$ input can be used to place the outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly.
$\overline{\mathrm{OE}}$ does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The 74ACT16823 is packaged in theTI shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.
The 54ACT16823 is characterized for operation over the full military temperature range of $55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. The 74 ACT 16823 is characterized for operation from $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$

| FUNCTION TABLE (each 9-bit stage) |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: |
| INPUTS |  |  |  |  | OUTPUT |
| $\overline{\mathrm{OE}}$ | $\overline{\text { CLR }}$ | CLKEN | CLK | D | Q |
| L | L | X | X | X | L |
| L | H | L | $\uparrow$ | H | H |
| L | H | L | $\uparrow$ | L | L |
| L | H | L | L | X | $Q_{0}$ |
| L | H | H | X | X | $Q_{0}$ |
| H | X | X | X | X | Z |

logic symbol $\dagger$

$\dagger$ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
logic diagram (positive logic)


To Eight Other Channels


## absolute maximum ratings over operating free-air temperature range (unless otherwise noted) $\dagger$

| Supply voltage range, $\mathrm{V}_{\mathrm{CC}}$ | 0.5 V to 7 V |
| :---: | :---: |
| Input voltage range, $\mathrm{V}_{\text {I }}$ (see Note 1) | -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$ |
| Output voltage range, $\mathrm{V}_{\mathrm{O}}$ (see Note 1) | -0.5 V to $\mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V}$ |
| Input clamp current, $\mathrm{I}_{\mathrm{IK}}\left(\mathrm{V}_{\mathrm{I}}<0\right.$ or $\left.\mathrm{V}_{\text {I }}>\mathrm{V}_{\mathrm{CC}}\right)$ | $\pm 20 \mathrm{~mA}$ |
| Output clamp current, $\mathrm{I}_{\mathrm{OK}}\left(\mathrm{V}_{\mathrm{O}}<0\right.$ or $\left.\mathrm{V}_{\mathrm{O}}>\mathrm{V}_{\mathrm{CC}}\right)$ | $\pm 50 \mathrm{~mA}$ |
| Continuous output current, $\mathrm{I}_{\mathrm{O}}\left(\mathrm{V}_{\mathrm{O}}=0\right.$ to $\left.\mathrm{V}_{\mathrm{CC}}\right)$ | $\pm 50 \mathrm{~mA}$ |
| Continuous current through $\mathrm{V}_{\mathrm{CC}}$ or GND | $\pm 450 \mathrm{~mA}$ |
| Maximum package power dissipation at $\mathrm{T}_{\mathrm{A}}=55$ | ge ........... 1.4 W |
| Storage temperature range, $\mathrm{T}_{\text {stg }}$ | $65^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ |

$\dagger$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The maximum package power dissipation is calculated using a junction temperature of $150^{\circ} \mathrm{C}$ and a board trace length of 750 mils.
recommended operating conditions (see Note 2)

|  |  |  | CT168 |  |  | CT168 |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | NOM | MAX | MIN | NOM | MAX | NIT |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage | 4.5 | 5 | 5.5 | 4.5 | 5 | 5.5 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | High-level input voltage | 2 |  | $\checkmark$ | 2 |  |  | V |
| $\mathrm{V}_{\mathrm{IL}}$ | Low-level input voltage |  |  | 0.8 |  |  | 0.8 | V |
| $\mathrm{V}_{1}$ | Input voltage | 0 |  | $\mathrm{V}_{\mathrm{CC}}$ | 0 |  | $\mathrm{V}_{\mathrm{CC}}$ | V |
| $\mathrm{V}_{\mathrm{O}}$ | Output voltage | 0 |  | $\mathrm{V}_{\mathrm{CC}}$ | 0 |  | $\mathrm{V}_{\mathrm{CC}}$ | V |
| ${ }^{\text {OH }}$ | High-level output current |  |  | -24 |  |  | -24 | mA |
| IOL | Low-level output current |  |  | 24 |  |  | 24 | mA |
| $\Delta t / \Delta \mathrm{v}$ | Input transition rise or fall rate | 0 |  | 10 | 0 |  | 10 | ns/V |
| $\mathrm{T}_{\mathrm{A}}$ | Operating free-air temperature | -55 |  | 125 | -40 |  | 85 | ${ }^{\circ} \mathrm{C}$ |

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS | Vcc | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | 54ACT16823 | 74ACT16823 | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP MAX | MIN MAX | MIN MAX |  |
| $\mathrm{V}_{\mathrm{OH}}$ | $\mathrm{I} \mathrm{OH}=-50 \mu \mathrm{~A}$ | 4.5 V | 4.4 |  | 4.4 | 4.4 | V |
|  |  | 5.5 V | 5.4 |  | 5.4 | 5.4 |  |
|  | $\mathrm{IOH}=-24 \mathrm{~mA}$ | 4.5 V | 3.94 |  | 3.8 | 3.8 |  |
|  |  | 5.5 V | 4.94 |  | 4.8 | 4.8 |  |
|  | $\mathrm{IOH}=-75 \mathrm{~mA} \dagger$ | 5.5 V |  |  | 3.85 | 3.85 |  |
| VOL | $\mathrm{IOL}=50 \mu \mathrm{~A}$ | 4.5 V |  | 0.1 | 0.1 | 0.1 | V |
|  |  | 5.5 V |  | 0.1 | 0.1 | 0.1 |  |
|  | $\mathrm{lOL}=24 \mathrm{~mA}$ | 4.5 V |  | 0.36 | 0.44 | 0.44 |  |
|  |  | 5.5 V |  | 0.36 | 8. 0.44 | 0.44 |  |
|  | $\mathrm{I}^{\text {OL }}=75 \mathrm{~mA} \dagger$ | 5.5 V |  |  | (1) 1.65 | 1.65 |  |
| 1 | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}$ or GND | 5.5 V |  | $\pm 0.1$ | $\pm 1$ | $\pm 1$ | $\mu \mathrm{A}$ |
| IOZ | $\mathrm{V}_{\mathrm{O}}=\mathrm{V}_{\mathrm{CC}}$ or GND | 5.5 V |  | $\pm 0.5$ | $\pm 5$ | $\pm 5$ | $\mu \mathrm{A}$ |
| ICC | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}$ or GND, $\quad \mathrm{IO}=0$ | 5.5 V |  | 8 | 80 | 80 | $\mu \mathrm{A}$ |
| ${ }^{\text {I }} \mathrm{CC} \mathrm{C}^{\ddagger}$ | One input at 3.4 V , Other inputs at $\mathrm{V}_{\mathrm{CC}}$ or GND | 5.5 V |  | 0.9 | 1 | 1 | mA |
| $\mathrm{C}_{\mathrm{i}}$ | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}$ or GND | 5 V |  | 3 |  |  | pF |
| $\mathrm{C}_{0}$ | $\mathrm{V}_{\mathrm{O}}=\mathrm{V}_{\mathrm{CC}}$ or GND | 5 V |  | 12 |  |  | pF |

$\dagger$ Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms .
$\ddagger$ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or $\vee_{\mathrm{CC}}$.
timing requirements over recommended operating free-air temperature range, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V} \pm 0.5 \mathrm{~V}$ (unless otherwise noted) (see Figure 1)

|  |  |  | $\mathrm{T}_{\mathrm{A}}=$ | $5^{\circ} \mathrm{C}$ | 54AC | 6823 | 74AC | 6823 |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX | MIN | MAX | MIN | MAX |  |
| $\mathrm{f}_{\text {clock }}$ | Clock frequency |  | 0 | 90 | 0 | 90 | 0 | 90 | MHz |
|  | Pulse duration | $\overline{\text { CLR }}$ low | 3.3 |  | 3.3 | « | 3.3 |  |  |
| tw | Puse duration | CLK high or low | 5.5 |  | 5.5 |  | 5.5 |  |  |
|  |  | $\overline{\text { CLR }}$ inactive | 0.5 |  | 0.5 |  | 0.5 |  |  |
| $t_{\text {su }}$ | Setup time before CLK $\uparrow$ | Data | 7 |  | 7 |  | 7 |  | ns |
|  |  | $\overline{\text { CLKEN }}$ Iow | 3.5 |  | 3.5 |  | 3.5 |  |  |
|  |  | Data | 0.5 |  | 0.5 |  | 0.5 |  |  |
| th | Hold time after CLK $\uparrow$ | $\overline{\text { CLKEN }}$ high or low | 2.5 |  | 2.5 |  | 2.5 |  | ns |

switching characteristics over recommended operating free-air temperature range,
$\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V} \pm 0.5 \mathrm{~V}$ (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  |  | 54ACT16823 |  | 74ACT16823 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX | MIN | MAX | MIN | MAX |  |
| $\mathrm{f}_{\max }$ |  |  | 90 |  |  | 90 | 2 | 90 |  | MHz |
| tPLH | CLK | Q | 4.2 | 7.5 | 10.6 | 4.2 | 12.1 | 4.2 | 12.1 | ns |
| tPHL |  |  | 4.8 | 8.3 | 11.5 | 4.8 | 12.9 | 4.8 | 12.9 |  |
| tPHL | $\overline{\mathrm{CLR}}$ | Q | 3.4 | 7.3 | 11.2 | 3.4 | 12.5 | 3.4 | 12.5 | ns |
| tPZH | $\overline{\mathrm{OE}}$ | Q | 2.4 | 5.9 | 9.5 | 2.4 | 10.7 | 2.4 | 10.7 | ns |
| tPZL |  |  | 3.3 | 7.1 | 11.3 | 3.3 | 12.8 | 3.3 | 12.8 |  |
| tPHZ | $\overline{O E}$ | Q | 5.5 | 7.6 | 9.7 | -5.5 | 10.3 | 5.5 | 10.3 | ns |
| tPLZ |  |  | 4.6 | 6.7 | 8.8 | 4.6 | 9.4 | 4.6 | 9.4 |  |

operating characteristics, $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$

| PARAMETER |  | TEST CONDITIONS |  | TYP | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Power dissipation capacitance per flip-flop | Outputs enabled | $C_{L}=50 \mathrm{pF}$, | $\mathrm{f}=1 \mathrm{MHz}$ | 42 | pF |
|  | Outputs disabled |  |  | 24 |  |

## PARAMETER MEASUREMENT INFORMATION



| TEST | S1 |
| :---: | :---: |
| ${ }^{\text {tPLH/tPHL }}$ | Open |
| tPLZ/tPZL | $2 \times V_{C C}$ |
| $\mathrm{t}_{\text {PHZ }} / \mathrm{t}^{\text {PZH }}$ | GND |



NOTES: A. $C_{L}$ includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $\mathrm{PRR} \leq 1 \mathrm{MHz}, \mathrm{Z}_{\mathrm{O}}=50 \Omega, \mathrm{t}_{\mathrm{r}}=3 \mathrm{~ns}, \mathrm{t}_{\mathrm{f}}=3 \mathrm{~ns}$.
D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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